

Search Notes

Application/Control No.

10/790,134

Examiner

Jean F. Duverne

Applicant(s)/Patent under
Reexamination

CHANG, CHIH-KAI

Art Unit

2839

SEARCHED

Class	Subclass	Date	Examiner
439	676	4/27/2005	JFD
	736		
	344		
	638-639		
	76.1		
	686		
	689	4/27/2005	JFD

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner